

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
P-4725-USAPPLICATION NO.
09/827,512INFORMATION DISCLOSURE
STATEMENT BY APPLICANTSAPPLICANTS
Shor et al.CONFIRMATION NO.
6126FILING DATE
04/05/01GROUP
2816

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<i>DL</i>	4,173,766	11/06/1979	Hayes	357 <i>365</i>	<i>23</i>	—
	4,742,491	05/03/1988	Liang et al.	<i>365</i>	<i>218</i>	—
	5,021,999	06/04/1991	Kohda et al.	<i>365</i>	<i>168</i>	—
	5,168,334	12/01/1992	Mitchell et al.	357 <i>365</i>	<i>324</i>	—
	5,241,497	08/31/1993	Komarek	<i>365</i>	<i>104</i>	—
	5,276,646	01/04/1994	Kim et al.	<i>365</i>	<i>189.09</i>	—
	5,280,420	01/18/1994	Rapp	<i>363</i>	<i>60</i>	—
	5,338,954	08/16/1994	Shimoji	257 <i>365</i>	<i>326</i>	—
	5,349,221	09/20/1994	Shimoji	257 <i>365</i>	<i>324</i>	—
	5,412,601	05/02/1995	Sawada et al.	<i>365</i>	<i>185</i>	—
	5,418,743	05/23/1995	Tomioka et al.	<i>365</i>	<i>189.01</i>	—
	5,424,978	06/13/1995	Wada et al.	<i>365</i>	<i>184</i>	—
	5,450,341	09/12/1995	Sawada et al.	<i>365</i>	<i>185</i>	—
	5,450,354	09/12/1995	Sawada et al.	<i>365</i>	<i>185</i>	—
	5,467,308	11/14/1995	Chang et al.	<i>365</i>	<i>185.01</i>	—
	5,477,499	12/19/1995	Van Buskirk et al.	<i>365</i>	<i>218</i>	—
	5,553,030	09/03/1996	Tedrow et al.	<i>365</i>	<i>226</i>	—
	5,559,687	09/24/1996	Nicollini et al.	<i>363</i>	<i>30</i>	—
	5,717,581	02/10/1998	Canclini	<i>363</i>	<i>60</i>	—
	5,726,946	03/10/1998	Yamagata et al.	<i>365</i>	<i>226</i>	—
	5,768,192	06/16/1998	Eitan	<i>365</i>	<i>185.24</i>	—
	5,825,686	10/20/1998	Schmitt-Landsiedel et al.	365 <i>365</i>	<i>185.03</i>	—
	5,946,258	08/31/1999	Evertt et al.	<i>365</i>	<i>226</i>	—
	6,011,725	01/04/2000	Eitan	<i>365</i>	<i>185.33</i>	—
	6,064,251	05/16/2000	Park	<i>327</i>	<i>536</i>	—
	6,075,402	06/13/2000	Ghilardelli et al.	327 <i>327</i>	536 <i>536</i>	—
	6,094,095	07/25/2000	Murray et al.	<i>327</i>	<i>589</i>	—
<i>X</i>	6,107,862	08/22/2000	Mukainakano et al.	<i>327</i>	<i>536</i>	—

EXAMINER

Wab/bb

DATE CONSIDERED

10/10/02

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicants.

FORM PTO-249 JUL 15 2002 PATENT & TRADEMARK OFFICE	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. P-4725-US	APPLICATION NO. 09/827,512
	INFORMATION DISCLOSURE STATEMENT BY APPLICANTS	APPLICANTS Shor et al.	CONFIRMATION NO. 6126
		FILING DATE 04/05/01	GROUP 2816

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<i>DZ</i>	6,130,572	10/10/2000	Ghilardelli et al.	<i>327</i>	<i>536</i>	—
<i>DZ</i>	6,163,048	12/19/2000	Hirose et al.	<i>365</i>	<i>185.01</i>	—
<i>DZ</i>	6,201,282	03/13/2001	Eitan	<i>257</i>	<i>390</i>	—

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FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
<i>DZ</i>	GB 2157489	10/23/1985	<u> </u>	<u> </u>	<u> </u>	X	<u> </u>

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL	
<i>DL</i>	Bude et al., "EEPROM/Flash Sub 3.0 V Drain-Source Bias Hot carrier Writing", IEDM 95, pp. 989-992.
<i>DL</i>	Bude et al., "Secondary Electron Flash - a High Performance, Low Power Flash Technology for 0.35 μ m and Below", IEDM 97, pp. 279-282.
<i>DL</i>	Bude et al., "Modeling Nonequilibrium Hot Carrier Device Effects", Conference of Insulator Specialists of Europe, Sweden, June 1997.

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